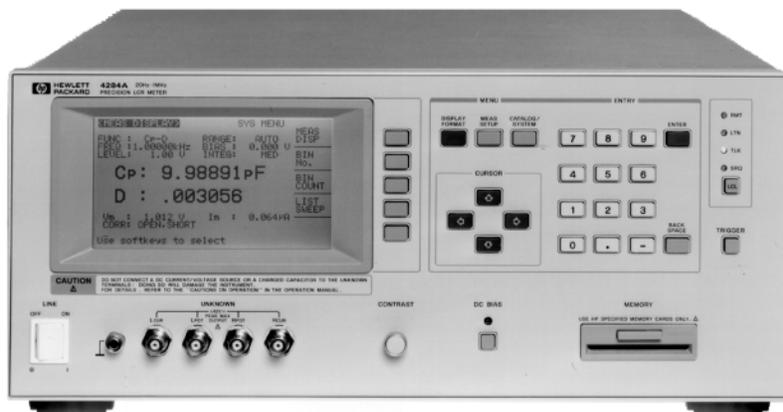


Measurement of Capacitance Characteristics of Liquid Crystal Cell

Application Note 369-7

HP 4284A Precision LCR Meter



Introduction

Today liquid crystals used in LCD displays are being used in a wider range of products than ever before, prompting the need for rapid liquid crystal application research. The properties of liquid crystal materials used for LCDs are evaluated using the data gained from voltage-capacitance characteristics measurement. The measurement technique presented in this application note describes how to take best advantage of the HP 4284A's powerful features when measuring capacitance while varying an AC signal voltage applied to the liquid crystal material under test. Capacitance characteristic measurements provide the researcher with information on critical parameters, such as the elastic constants which determines the threshold voltage of the liquid crystal material and the acuteness of its threshold characteristics.

• Problems

One problem encountered when using conventional instruments to measure voltage-capacitance characteristics is the maximum test signal voltage is not high and therefore the test signal must be voltage amplified (using an external amplifier) before being

applied to the liquid crystal material under test. Adding an external amplifier not only introduces additional measurement error, but also complicates the measurement procedure, because the voltage applied to the material under test must be accurately known to obtain correct and accurate measurement results.

• Solutions Offered by The HP 4284A

Using the HP 4284A Precision LCR Meter with Option 001 provides a test signal level of 20 Vrms, making it optimal for measuring the capacitance characteristics of liquid crystal materials. Moreover, the test signal voltage can be set with a resolution of 1%. In addition to the HP 4284A's test frequency range of 20 Hz to 1 MHz, its basic measurement accuracy of 0.05%, and its 6-digit measurement resolution contribute strongly to your ability to perform highly accurate measurements under diverse measurement conditions. The voltage applied to the material being tested device can be measured using the HP 4284A's monitoring function to meet accurate measurement requirements.

This application note will guide you in using the HP 4284A to make measurements to determine the voltage-capacitance characteristics of experimental liquid crystal samples.

Measurement of Test Signal Voltage Versus Capacitance Characteristic (Freedericksz Transition)

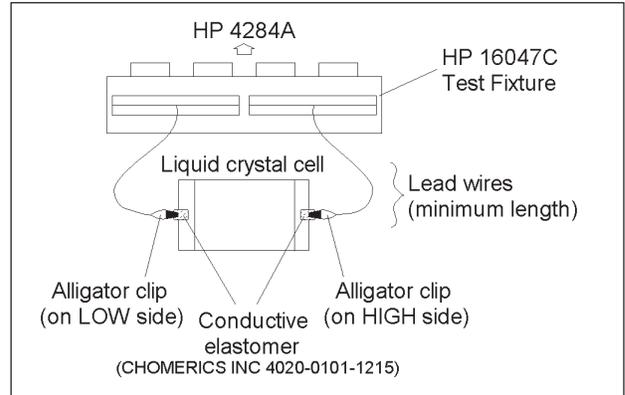
• Connections

Figure 1 shows the connections between a liquid crystal cell and the HP 4284A. The liquid crystal cell is in the form of liquid crystals sandwiched between two glass plates which have electrodes installed. In this experimental measurement procedure, the electrodes of the liquid crystal cell are held using alligator clips and a conductive elastomer with the lead wires connected to an HP 16047C test fixture (see Figure 1a).

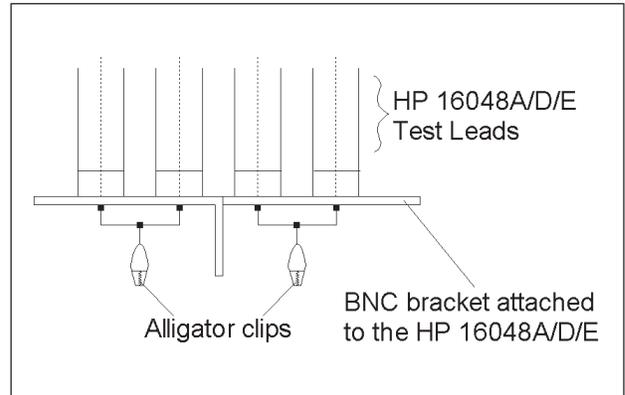
The OPEN/SHORT compensation function is used to eliminate the effects of the lead wires and alligator clips connected to the test fixture, but it is best to keep the length of the lead wires to a minimum for stable and repeatable measurements. If the HP 4284A must be located some distance from the sample cell which, for example, must be placed into a thermostatic chamber, the cables can be extended by 1 m, 2 m, and 4 m respectively using the HP 16048A/D/E Test leads (see Figure 1b). The HP 4284A provides a correction function for the HP 16048A/D/E, so that accurate measurement is insured with minimum effects due to extending the cable. (Note that the HP 16048D/E requires an Option 006 HP 4284A.)

• Measurement Example

Figure 2 shows voltage-capacitance characteristics of liquid crystal cells measured using an Option 001 HP 4284A. The graph shows measurement results plotted by an HP 9000 Series 300 Technical Computer system where a 1 kHz test signal was varied from 0.1 V to 20 V in 0.1 V steps. Figure 2 reveals that the threshold voltage V_c required for obtaining the elastic constants was accurately measured. The test signal voltage can be varied high enough for point C// to be measured accurately. A single cell can be used to determine the dielectric constant when the liquid crystals are oriented vertically to the detector (ϵ_{\perp}) and when they are oriented parallel to the detector ($\epsilon_{//}$), the splay elastic constant K_{11} , and the bend elastic constant K_{33} respectively.



(a) When using the HP 16047C



(b) When cable is extended

Figure 1. Connection diagram

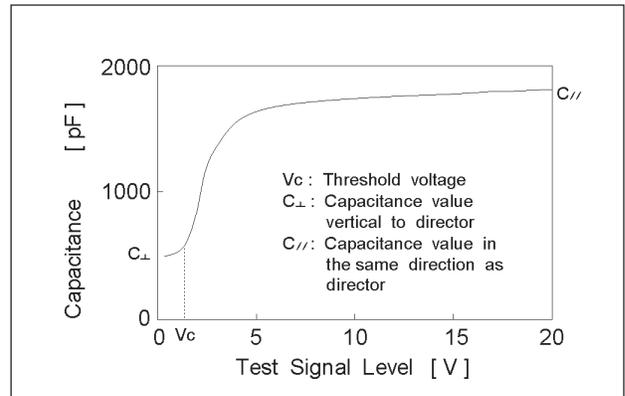


Figure 2. Voltage-capacitance Characteristics Measurement Results

Conclusion

The HP 4284A's wide test signal voltage range outperforms conventional LCR meters, and therefore contributes to easier measurement to determine the voltage-capacitance characteristics of liquid crystal materials. This will pave the way for efficient evaluation of new liquid crystal materials for new product applications, or the bottom line is, the HP 4284A is a powerful tool with which you will decrease your time to market!

Reference: Liquid crystals - Basics,
Kohji Okano and Shunsuke Kobayashi,
(Tokyo: Baihukan, 1985), PP. 216-220.

For more information about Hewlett-Packard test & measurement products, applications, services, and for a current sales office listing, visit our web site, <http://www.hp.com/go/tmdir>. You can also contact one of the following centers and ask for a test and measurement sales representative.

United States:

Hewlett-Packard Company
Test and Measurement Call Center
P.O. Box 4026
Englewood, CO 80155-4026
1 800 452 4844

Canada:

Hewlett-Packard Canada Ltd.
5150 Spectrum Way
Mississauga, Ontario
L4W 5G1
(905) 206 4725

Europe:

Hewlett-Packard
European Marketing Centre
P.O. Box 999
1180 AZ Amstelveen
The Netherlands
(31 20) 547 9900

Japan:

Hewlett-Packard Japan Ltd.
Measurement Assistance Center
9-1, Takakura-Cho, Hachioji-Shi,
Tokyo 192, Japan
Tel: (81) 426 56 7832
Fax: (81) 426 56 7840

Latin America:

Hewlett-Packard
Latin American Region Headquarters
5200 Blue Lagoon Drive
9th Floor
Miami, Florida 33126
U.S.A.
Tel: (305) 267-4245
(305) 267-4220
Fax: (305) 267-4288

Australia/New Zealand:

Hewlett-Packard Australia Ltd.
31-41 Joseph Street
Blackburn, Victoria 3130
Australia
Tel: 1 800 629 485 (Australia)
0800 738 378 (New Zealand)
Fax: (61 3) 9210 5489

Asia Pacific:

Hewlett-Packard Asia Pacific Ltd.
17-21/F Shell Tower, Times Square,
1 Matheson Street, Causeway Bay,
Hong Kong
Tel: (852) 2599 7777
Fax: (852) 2506 9285